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JCO9 Rec'd PCT/PTO 07 OCT 2005

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

EXPRESS MAIL NO. EV351242295US

Applicant : Maxime Makarov, et al.
Application No. : N/A
Filed : October 7, 2005
Title : CONTROLLING THE SPATIO-TEMPORAL UNIFORMITY OF A
PULSED GAS LASER BEAM
Grp./Div. : N/A
Examiner : N/A
Docket No. : 56136/DBP/N75

INFORMATION DISCLOSURE STATEMENT
37 CFR § 1.97(b)

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

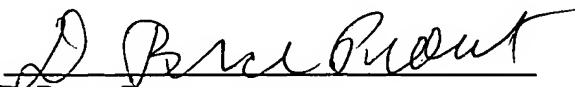
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October 7, 2005

Commissioner:

In compliance with the duty of disclosure under 37 CFR §§ 1.56, 1.97 and 1.98, and in accordance with the provisions in the Manual of Patent Examining Procedure §§ 609 and 707.05(b), enclosed is FORM PTO/SB/08A/B listing the references that are known to applicant. Copies of the listed "Foreign Patent Documents" and "Other Documents" are enclosed. This filing is timely because it is made during one of the periods described in 37 CFR § 1.97(b).

It is respectfully requested that the listed references be considered in the examination of this application and identified on the list of references cited on the patent issuing for this application. Applicant also requests that an initialed copy of FORM PTO/SB/08A/B be entered in the application file and returned to applicant with the next communication from the Office in accordance with MPEP § 609.

Respectfully submitted,
CHRISTIE, PARKER & HALE, LLP

By 
D. Bruce Prout
Reg. No. 20,958
626/795-9900

DBP/aam
Enclosures: Form PTO/SB/08A/B, w/references
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FORM PTO/SB/08A/B (10-01) Substitute for PTO-1449A/B	Attorney Docket Number	56136/DBP/N75
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)	Application Number	N/A
	Filing Date	October 7, 2005
	Applicant(s)	Maxime Makarov, et al.
	Group Art Unit	N/A
	Examiner Name	N/A

U.S. PATENT DOCUMENTS				
EXAMINER INITIALS	Cite No. ¹	DOCUMENT NUMBER Number - Kind Code ² (If Known)	Publication Date MM-DD-YYYY	Name of Patentee
		5,048,045	09-10-1991	Noda, et al.
		5,778,046	07-07-1998	Molloi, et al.

FOREIGN PATENT DOCUMENTS					
EXAMINER INITIALS	Cite No. ¹	FOREIGN PATENT DOCUMENT Country Code ³ - Number ⁴ - Kind Code ⁵ (If Known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	T ⁶ (✓)
		EP 0 496 438 A1	07-29-1992	Stegehuis	
		JP 2002 170767 (ON ORDER)	06-14-2002	Nakasuji	Patent Abstract of Japan

OTHER DOCUMENTS		
EXAMINER INITIALS	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article, title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
		International Search Report dated 02-01-2005 corresponding to PCT/FR2004/000557
		ERNST, "UNIFORM-FIELD ELECTRODES WITH MINIMUM WIDTH" OPTICS COMMUNICATIONS, 03-15-1984, pp. 275-277, Volume 49, number 4, North-Holland Publishing Co. Amsterdam, NL, XP000707576
		STAPPAERTS, "A novel analytical design method for discharge laser electrode profiles" Appl. Phys. Lett., 06-15-1982, pp. 1018-1019, Vol. 40, No. 12, American Institute of Physics, N.Y., U.S.A., XP000706421
		MIZOGUCHI, ET AL., "Rapid Discharge-Pumped Wide Aperture X-ray Preionized KrF Laser" Applied Physics B Photophysics and Laser Chemistry, 03-1991, pp.195-199, vol. B52, no. 3, Springer Verlag. Heidelberg, DE, XP009021400
		F A VAN GOOR, "Fast rise time x-ray pre-ionization source using a corona plasma cathode" Journal of Physics D: Applied Physics, 03-14-1993, pp. 404-409, vol. 26, No. 3, IOP Publishing Ltd., Bristol, GB, XP000360391

EXAMINER SIGNATURE	DATE CONSIDERED
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. ¹ Applicant's unique citation designation number (optional). ² See Kinds Codes of USPTO Patent Documents at www.pto.gov or MPEP 901.4. ³ Enter Office that issued the document, by the two-letter code (WIPO standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English Language Translation is attached.	

FORM PTO/SB/08A/B (10-01) Substitute for PTO-1449A/B	Attorney Docket Number	56136/DBP/N75
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OTHER DOCUMENTS		
EXAMINER INITIALS	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article, title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
		BISHOP, ET AL., "Axial x-ray preionization of high-pressure gas lasers" Conference on Lasers and Electro Optics (CLEO), 05-21-1985, p. 116, Baltimore, Maryland, May 21-24, 1985, New York, IEEE, US, XP000712882
		TUCKER, ET AL., "High-Pressure Infrared Xenon Laser with X-Ray Preionization" IEEE Photonics Technology Letters, 08-01-1989, pp. 193-195, vol. 1, no. 8, IEEE Inc., New York, US, XP000053589
		JAYARAM ET AL., "X-ray preionization of self-sustained, transverse excitation CO ₂ laser discharges" J. Appl. Phys. 09-01-1985, pp. 1719-1726, vol. 58, no. 5, American Institute of Physics, N.Y., US, XP000707078
		SHIELDS, ET AL., "SHORT PULSE X-RAY PREIONIZATION OF A HIGH PRESSURE XeCl GAS DISCHARGE LASER" OPTICS COMMUNICATIONS, 06-15-1982, PP. 128-132, Volume 42, number 2, North-Holland Publishing Co. Amsterdam, NL, XP000707870
		LEVATTER, ET AL., "Low energy x-ray preionization source for discharge excited lasers" Rev. Sci. Instrum., 11-1-1981, pp. 1651-1654, vol. 52, no. 11, American Institute of Physics, N.Y., US, XP000711240
		MIDORIKAWA, ET AL., "X-Ray Preionization of rare-Gas-Halide Lasers" IEEE JOURNAL OF QUANTUM ELECTRONICS, 03-01-1984, pp. 198-205, vol. QE-20, no. 3, IEEE Inc. N.Y., US, XP000705627
		TALLMAN, ET AL., "Determination of the minimum x-ray flux for effective preionization of an XeCl laser" Appl. Phys. Lett., 01-15-1983, pp. 149-151, Vol. 42, No. 2, American Institute of Physics, N.Y., US, XP000705689
		CHANG, "Improved Uniform-Field Electrode Profiles for TEA Laser and High-Voltage Applications" Rev. Sci. Instrum., 1973, pp. 405-407, vol. 44, no. 4 (ON ORDER)

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